


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/604,796	CHANG ET AL.	
	Examiner	Art Unit	
	Hashem Farrokh	2187	

SEARCHED			
Class	Subclass	Date	Examiner
711	1-3,101-105,111-115,167	7/30/2005	HF
712	1,38,43	7/30/2005	HF

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
PALM Inventor Search	7/28/2005	HF
Brian Peugh	8/1/2005	HF